

25N20

Power MOSFET

25A, 200V N-CHANNEL ENHANCEMENT MODE POWER MOSFET

DESCRIPTION

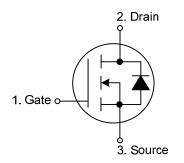
The UTC **25N20** is an N-channel enhancement mode power MOSFET and it uses UTC's perfect technology to provide designers with fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

It is generally suitable for all commercial-industrial applications and DC/DC converters requiring low voltage.

FEATURES

- * $R_{DS(ON)}$ < 160 m Ω @ V_{GS} =10V, I_D =16A
- * Single Drive Requirement
- * Low Gate Charge
- * RoHS Compliant

SYMBOL

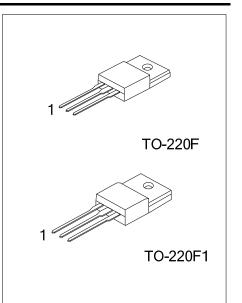


ORDERING INFORMATION

	Ordering	Deekege	Pin Assignment			Dealing		
	Lead Free	Halogen Free	Package	1	2	3	Packing	
	25N20L-TF3-T	25N20G-TF3-T	TO-220F	G	D	S	Tube	
	25N20L-TF1-T	25N20G-TF1-T	TO-220F1	G	D	S	Tube	
Note:	Pin Assignment: G: G	ate D: Drain S: Source						







ABSOLUTE MAXIMUM RATINGS

PARAMETER		SYMBOL	RATINGS	UNIT	
Drain Source Voltage		V _{DSS}	200	V	
Gate Source Voltage		V _{GSS}	±20	V	
Continuous Drain Current	T _C =25°C	Ι _D	25	А	
(V _{GS} =10V)	$T_{\rm GS}$ =10V) $T_{\rm C}$ = 100°C		15.86	А	
Pulsed Drain Current (Note 2)		I _{DM}	80	А	
Total Power Dissipation $(T_{C}=25^{\circ}C)$		P _D	50	W	
Operating Junction Temperature		TJ	-55 ~ +150	°C	
Storage Temperature		T _{STG}	-55 ~ +150	°C	

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged. Absolute maximum ratings are stress ratings only and functional device operation is not implied.

2. Pulse width limited by max. junction temperature.

THERMAL DATA

PARAMETER	SYMBOL	RATINGS	UNIT	
Junction to Ambient	θ _{JA}	62.5	°C/W	
Junction to Case	θ _{JC}	2.5	°C/W	

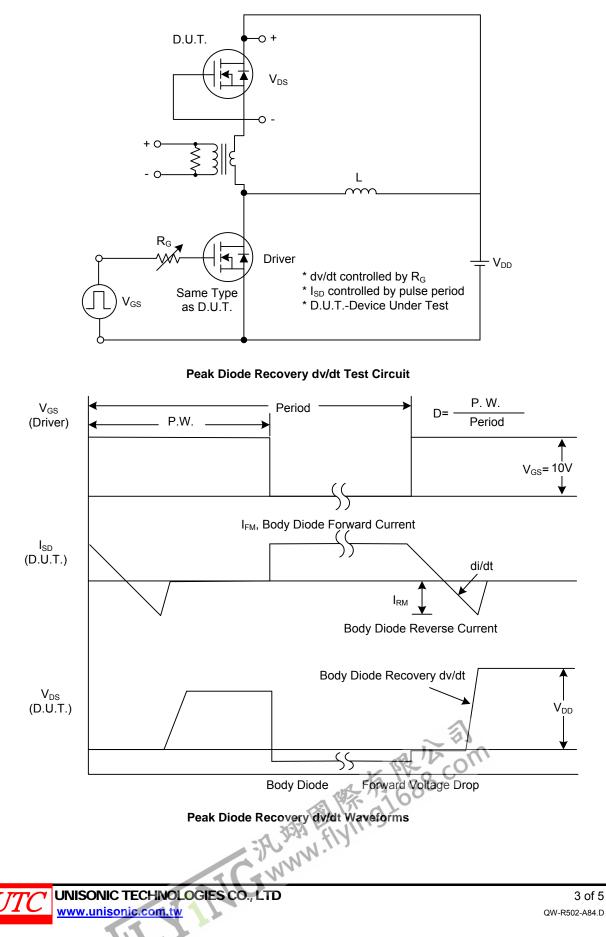
ELECTRICAL CHARACTERISTICS (TJ=25°C, unless otherwise specified)

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT		
OFF CHARACTERISTICS		•						
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V, I _D =250µA	200			V		
Breakdown Voltage Temperature Coefficient		Reference to 25° C , I _D =1mA		0.14		V/°C		
Drain-Source Leakage Current	I _{DSS}	V _{DS} =100V, V _{GS} =0V, T _J =25°C V _{DS} =80V, V _{GS} =0V,T _J =150°C			1 100	μΑ μΑ		
Gate-Source Leakage Current	I _{GSS}	V _{GS} =±20V			±100	nA		
ON CHARACTERISTICS								
Gate Threshold Voltage	V _{GS(TH)}	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$			4	V		
Static Drain-Source On-Resistance (Note)	R _{DS(ON)}	V _{GS} =10V, I _D =16A		112	160	mΩ		
Forward Transconductance	g fs	V _{DS} =10V, I _D =16A		14		S		
DYNAMIC PARAMETERS		-						
Input Capacitance	C _{ISS}	V _{DS} =25V, V _{GS} =0V, f=1.0MHz		1000	1700	рF		
Output Capacitance	C _{OSS}			240		pF		
Reverse Transfer Capacitance	C _{RSS}			25		рF		
SWITCHING PARAMETERS				i				
Turn-ON Delay Time ¹	t _{D(ON)}	V_{DD} =30V, I _D =0.5A, R _G =25m Ω , V_{GS} =10V, R _D =3.125 Ω		56		ns		
Turn-ON Rise Time	t _R			75		ns		
Turn-OFF Delay Time	t _{D(OFF)}			240		ns		
Turn-OFF Fall-Time	t⊧			100		ns		
Total Gate Charge (Note)	Q _G	V _{GS} =10V, V _{DS} =50V, I _D =1.3A		35	40	nC		
Gate Source Charge	Q _{GS}			8		nC		
Gate Drain Charge	Q_{GD}			9.7		nC		
SOURCE- DRAIN DIODE RATINGS AND C	HARACTERI	STICS	2	i				
Drain-Source Diode Forward Voltage (Note)	V _{SD}	I _S =25A, V _{GS} =0V	*		1.3	V		
Reverse Recovery Time	t _{RR}	I _S =25A,V _{GS} ≠0V,		90		ns		
Reverse Recovery Charge	Q _{RR}	dl/dt=100A/µs		380		nC		
Reverse Recovery Charge Q _{RR} dl/dt=100A/µs 380 nC Note: Pulse Test : Pulse width ≤ 300µs, Duty cycle ≤ 2%. 380 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100 100								



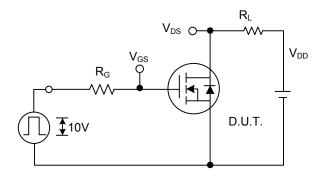
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TEST CIRCUITS AND WAVEFORMS

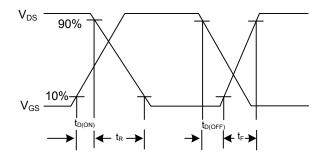


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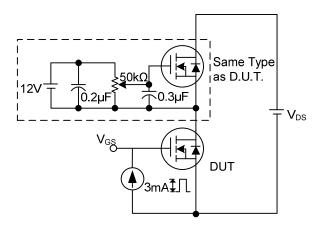
TEST CIRCUITS AND WAVEFORMS (Cont.)



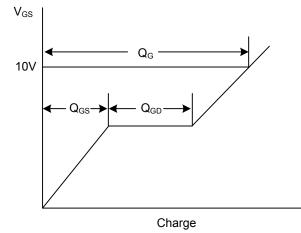




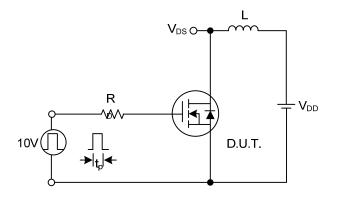
Switching Waveforms



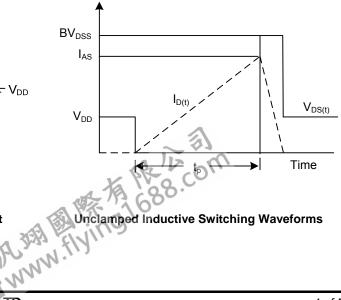




Gate Charge Waveform

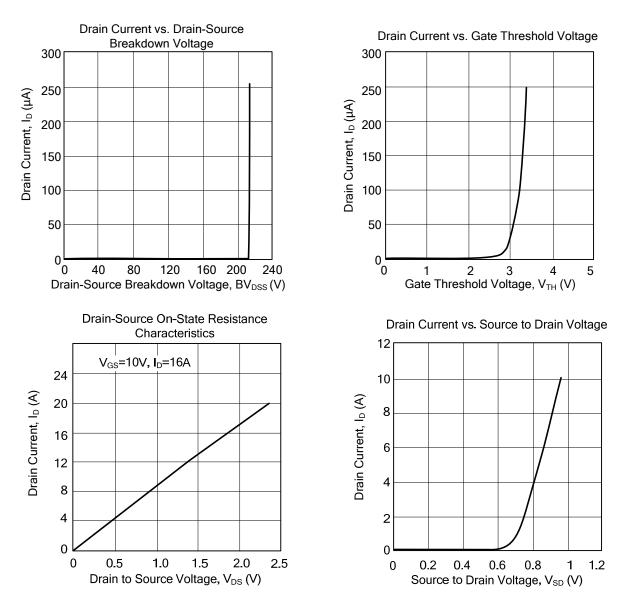


Unclamped Inductive Switching Test Circuit





TYPICAL CHARACTERISTICS



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